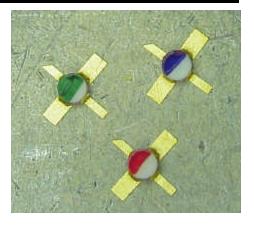


- FEATURES
 - 0.7 dB Noise Figure at 12 GHz
 - 12 dB Associated Gain at 12 GHz
 - 0.6 dB Noise Figure at 2 GHz
 - 14 dB Associated Gain at 2 GHz
 - Low DC Power Consumption



DESCRIPTION AND APPLICATIONS

The LPS200P70 is a packaged Aluminum Gallium Arsenide / Indium Gallium Arsenide (AlGaAs/InGaAs) Pseudomorphic High Electron Mobility Transistor (PHEMT), utilizing an Electron-Beam direct-write 0.25 μ m by 200 μ m Schottky barrier gate. The recessed "mushroom" Ti/Pt/Au gate structure minimizes parasitic gate-source and gate resistances. The epitaxial structure and processing have been optimized for high dynamic range. The LPS200's active areas are passivated with Si₃N₄, and the P70 ceramic package is ideal for low-cost, high-performance applications that require a surface-mount package.

Typical applications include low noise receiver preamplifiers for commercial applications including Cellular/PCS systems and broad band commercial instrumentation.

Test Conditions Max Units Parameter Symbol Min Тур Saturated Drain-Source Current** $V_{DS} = 2 V; V_{GS} = 0 V$ 15 50 mA I_{DSS} Noise Figure NF $V_{DS} = 2 V; I_{DS} = 25\% I_{DSS}$ 0.7 1.3 dB Associated Gain at minimum NF $V_{DS} = 2 V; I_{DS} = 25\% I_{DSS}$ GA 10.5 12 dB $V_{DS} = 2 V; V_{GS} = 0 V$ Transconductance 60 80 mS GM Gate-Source Leakage Current $V_{GS} = -3 V$ 1 15 I_{GSO} μA Vp $V_{DS} = 2 V; I_{DS} = 1 mA$ -0.25 -0.8 -1.5 V Pinch-Off Voltage

ELECTRICAL SPECIFICATIONS @ T_{Ambient} = 25°C*

*frequency=12 GHz, unless otherwise noted

**Formerly binned as: LPS200P70-1 = 15-30 mA and LPS200P70-2 = 31-50 mA



ABSOLUTE MAXIMUM RATINGS

| Parameter | Symbol | Test Conditions | Min | Max | Units |
|-------------------------------|------------------|--------------------------------------|-----|------------------|-------|
| Drain-Source Voltage | V _{DS} | $T_{Ambient} = 22 \pm 3 \ ^{\circ}C$ | | 4 | V |
| Gate-Source Voltage | V _{GS} | $T_{Ambient} = 22 \pm 3 \ ^{\circ}C$ | | -2 | V |
| Drain-Source Current | I _{DS} | $T_{Ambient} = 22 \pm 3 \ ^{\circ}C$ | | I _{DSS} | mA |
| Gate Current | I _G | $T_{Ambient} = 22 \pm 3 \ ^{\circ}C$ | | 2 | mA |
| RF Input Power | P _{IN} | $T_{Ambient} = 22 \pm 3 \ ^{\circ}C$ | | 50 | mW |
| Channel Operating Temperature | T _{CH} | $T_{Ambient} = 22 \pm 3 \ ^{\circ}C$ | | 175 | °C |
| Storage Temperature | T _{STG} | — | -65 | 175 | °C |
| Total Power Dissipation | P _{TOT} | $T_{Ambient} = 22 \pm 3 \ ^{\circ}C$ | | 300 | mW |

Notes:

- Operating conditions that exceed the Absolute Maximum Ratings could result in permanent damage to the device.
- Power Dissipation defined as: $P_{TOT} \equiv (P_{DC} + P_{IN}) P_{OUT}$, where
 - P_{DC}: DC Bias Power P_{IN}: RF Input Power

 P_{OUT} : RF Output Power

- Absolute Maximum Power Dissipation to be de-rated as follows above 25°C:
 - $P_{TOT} = 300 \text{mW} (3.5 \text{mW}^{\circ}\text{C}) \text{ x } T_{HS}$
 - where T_{HS} = heatsink or ambient temperature.
- This PHEMT is susceptible to damage from Electrostatic Discharge. Proper precautions should be used when handling these devices.

• HANDLING PRECAUTIONS

To avoid damage to the devices care should be exercised during handling. Proper Electrostatic Discharge (ESD) precautions should be observed at all stages of storage, handling, assembly, and testing. These devices should be treated as Class 1A (0-500 V). Further information on ESD control measures can be found in MIL-STD-1686 and MIL-HDBK-263.

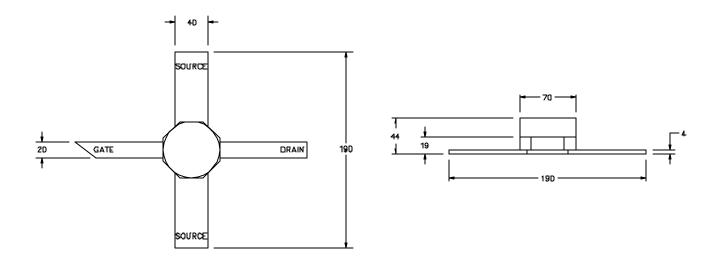
APPLICATIONS NOTES & DESIGN DATA

Applications Notes are available from your local Filtronic Sales Representative or directly from the factory. Complete design data, including S-parameters, noise data, and large-signal models are available on the Filtronic web site.



PACKAGE OUTLINE

(dimensions in mils)



All information and specifications are subject to change without notice.